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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  <i>(use as many sheets as necessary)</i>		<b>Complete if Known</b>			
		Application Number	10/814,959		
		Filing Date	03/31/2004		
		First Named Inventor	Ustuner et al.		
		Group Art Unit	3737		
		Examiner Name	Joel Lamprecht		
Sheet	1	of	1	Attorney Docket Number	2004P01660US

OTHER NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No.†	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issu number(s), publisher, city and/or country where published	T <sup>2</sup>
	A1	Blocked Element Compensation In Phased Array Imaging Li, P.-C.; Flax, S.W.; Ebbini, E.S.; Oapos; and Donnell, M. Ultrasonics, Ferroelectrics and Frequency Control, IEEE Transactions on Volume 40, Issue 4, Jul 1993 Page(s): 283 - 292	
	A2	A Fourier Transform-Based Sidelobe Reduction Method In Ultrasound Imaging Mok-Kun Jeong Ultrasonics, Ferroelectrics and Frequency Control, IEEE Transactions on Volume 47, Issue 3, May 2000 Page(s): 759 - 763	
	A3	Coherence factor of speckle from a multi-row probe Hollman, K.W.; Rigby, K.W.; and O'Donnell, M. Ultrasonics Symposium, 1999. Proceedings. 1999 IEEE Volume 2, 17-20 Oct. 1999 Page(s): 1257 - 1260 vol.2	
	A4	Efficient parallel adaptive aberration correction Krishnan, S.; Rigby, K.W.; and O'Donnell, M. Ultrasonics, Ferroelectrics and Frequency Control, IEEE Transactions on Volume 45, Issue 3, May 1998 Page(s): 691 - 703	
	A5	Adaptive compensation of phase and magnitude aberrations Krishnan, S.; Pai-Chi Li; and O'Donnell, M. Ultrasonics, Ferroelectrics and Frequency Control, IEEE Transactions on Volume 43, Issue 1, Jan. 1996 Page(s): 44 - 55	

Examiner Signature	/Joel Lamprecht/	Date Considered	03/24/2010
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

†Unique citation designation number. ‡Applicant is to place a check mark here if English language Translation is attached.